## Sparch Notes

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Application/Control No.	Applicant(s)/Patent Under Reexamination
10568392	MIHARA ET AL.

Examiner Art Unit Chang-Yu Wang 1649

	SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Sequence search: SEQ ID NOs:1-4 regular and oligomer search. See search results in SCORE (1/13/09).	3/2/09	CYW
EAST, STN: search strategy attached (updated)	3/2/09	CYW
Inventor name search: EAST, STN, PALM (updated)	3/2/09	CYW
PLUS search from STIC. See search results in eDAN (2/17/09).	3/2/09	CYW

	INTERFERENCE SEARCH		
Class	Subclass	Date	Examiner

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